

<b>Notice of References Cited</b>	Application/Control No. 10/796,514	Applicant(s)/Patent Under Reexamination SNYDER ET AL.	
	Examiner Su C. Kim	Art Unit 2823	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,737,716 b1	05-2004	Matsuo et al.	257/406
	B	US-5,140,383	08-1992	Morris et al.	257/477
	C	US-4,312,113	01-1982	Calviello, Joseph A.	438/572
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Byiung Hun Lee et al. ,Dec. 1999, IEDM Technical Digest, international 5-8, pages 133-136
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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